

<b>Notic of Referenc s Cited</b>	Application/Control No. 10/037,587	Applicant(s)/Patent Under Reexamination MOTOMIYA, SEIYA	
	Examiner Brian P. Egan	Art Unit 1772	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,885,677	03-1999	Gosselin et al.	428/40.1
	B	US-5,866,220	02-1999	Rusincovitch et al.	428/40.1
	C	US-6,045,646	04-2000	Yoshikawa et al.	156/240
	D	US-5,932,352	08-1999	Higgins	428/423.1
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.